

Source	Value	Affected sample	Type	Effect on the total yield
Stat. unc. in $C(i, j)$	3–60%	bkg.	bin-by-bin	—
Extrapolation unc. in $C(i, j)$	—	bkg.	shape	—
Unc. in $f_{1D}(i)$	—	bkg.	shape	—
Integrated luminosity	2.5%	signal	norm.	2.5%
Muon id. and trigger efficiency	2% per muon	signal	norm.	4%
Track id. efficiency	4–12% per track	signal	shape	10–18%
MC stat. unc. in signal yields	8–100%	signal	bin-by-bin	5–20%
Theoretical uncertainties in the signal acceptance				
μ_R and μ_F variations		signal	norm.	0.8–2%
PDF		signal	norm.	1–2%
Theoretical uncertainties in the signal cross sections				
$\mu_{R,F}$ variations (ggF)	5–7%	signal	norm.	5–7%
$\mu_{R,F}$ variations (other processes)	0.4–9%	signal	norm.	<0.5%
PDF (ggF)	3.1%	signal	norm.	3.1%
PDF (other processes)	2.1–3.6%	signal	norm.	<0.5%